# Insights into the oxidation mechanisms of Ni particles using environmental TEM

Q. Jeangros\*, C. Hébert, A. Hessler-Wyser I.Van herle<sup>2</sup>

T.W. Hansen, J.B. Wagner<sup>3</sup>

R.E. Dunin-Borkowski<sup>4</sup>

Nickel oxidation

Ni + ½ O2 → NiO

TMF







with Electrons,
Jülich Research Centre, Germany

**Objectives** 

Model system to study oxidation

Solid oxide fuel cells

Technical University of Denmark



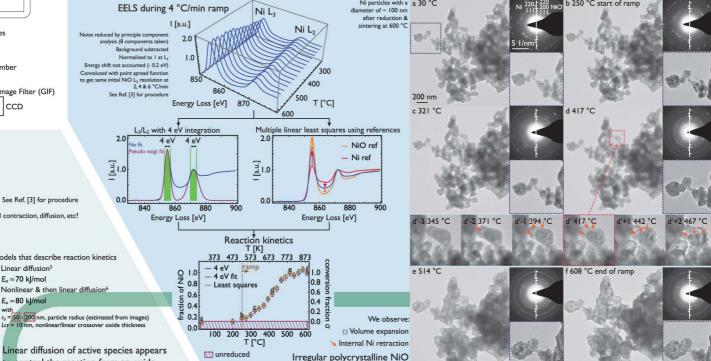
Correlate structural & chemical changes occurring during oxidation of Ni particles to NiO using environmental TEM

Understand oxidation mechanisms of Ni & their effect on

\* quentin.jeangros@epfl.ch

### A detailed understanding of the mechanisms controlling oxidation is required the resulting structure at the nm-scale Need for a characterization technique that can directly relate chemistry & structure at the nm-scale under relevant oxidation conditions $\frac{1}{2} \frac{1}{2} \frac{1$ Transition between nonlinear & linear diffusion regimes Environmental transmission electron microscopy (ETEM) FEG electron source Differentially pumped 300 kV FEITITAN<sup>2</sup> Reduction<sup>3</sup> & then oxidation Extraction anode Gatan 652 DT inconel heating holde Characterize system evolution during oxidation inside ETEM s/monochromato Commercial NiO powder on Au-SiO grids (crystallite size of ~ 100 nm by XRD) Imaging, diffraction, electron energy loss spectroscopy (EELS) CI 1.3 mbar H<sub>2</sub> 2 ml<sub>N</sub>/min HRTEM in 10<sup>-6</sup> mbar 2 ml<sub>N</sub>/mir NiO nucleation on Ni due to Po Random Ni/NiO orientation Built-in electric field driven NiO film growth up to 2-3 nm NiO growth rate negligible at a thickness of > 2-3 nm Gas Inlet

# Imaging, diffraction & EELS during oxidation up to 600 °C in 3.2 mbar of O2



integration 7 [I 573 673

Analysis of kinetics

 $= Ae^{\frac{-E_a}{R^2}}f(\alpha) \frac{\text{reaction model?}}{\text{nucleation, geom}}$  pre-exponential factor?

obtained by EELS

Models that describe reaction kinetics  $E_a \approx 70 \text{ kl/mol}$ 

Gatan Image Filter (GIF)

E<sub>a</sub> ≈ 80 kl/mol

ear diffusion of active species appears to control the reaction from an oxide thickness of ~ 10 nm up to full oxidation ch active species? How does it diffuse?

ic models allow to calculate  $k_p$  ~ reaction speed

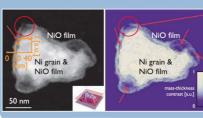
As the reaction appears mainly controlled by lineal diffusion,  $k_p$  is directly related to diffusion coefficient of Ni & O in NiO

Linear diffusion of Ni2+ along NiO grain boundaries seems to be the

These results are comparable to work done ex situ, similar to literature for oxide films > 1  $\mu m$ 

2) Built-in electric field due to space charge

# STEM HAADF at 300 °C in 3.2 mbar of O<sub>2</sub>



structures with internal voids

Fracture of the NiO film in curved regions due to geometrically induced stress

Nucleation of voids at NiO/Ni interfaces as Ni2+ diffusion is several orders of magnitude faster than O2- diffusion

# — 200 nm \_ − Lin 10 . 10-13 2.5 μm Karmhag<sup>7</sup> Experimen 10<sup>1</sup> 10 20 Ni<sup>2+</sup> diffusion in NiO lattice is Ni2+ diffusion in NiO grain boundaries

main rate-controlling mechanism

Does that description make sense? Here  $E_a$  (70-80 kJ/mol)  $\leq E_a$  for  $Ni^{2+}$  diffusion along NiO grain boundaries (171 kl/mol<sup>1</sup>)! However, two mechanisms lower Ea without changing the diffusion mechanism:

I) NiO grain growth decreases the number of fast diffusion paths as the oxide film grows

when the oxide film is thin (< I um)

## Oxidation mechanisms of Ni particles

2 As the temperature increases, Ni<sup>2+</sup> diffuses through the NiO grain boundaries. This process might be field-assisted. As O<sup>2-</sup> inwards diffusion is much slower, vacancies are injected at the NiO/Ni interfaces & voids nucleate

vacancies in flat regions unlike in curved areas, where NiO/Ni contact is lost quickly to geometrically induced stress, O<sub>2</sub> perme ates through the crack and reacts directly

which creates a large electric field in the film